

11:45	High resolution imaging of light-activated copper impurities in multicrystalline silicon wafers by photoluminescence Chiara Modanese, Alessandro Inglese, Alessia Focareta, Florian Schindler, Jonas Schön, Martin C. Schubert, Hele Savin Chiara Modanese, Alessandro Inglese, Alessia Focareta, Hele Savin - Department of Electronics and Nanoengineering, Aalto University, Espoo, Finland, Florian Schindler, Jonas Schön, Martin C. Schubert - Fraunhofer Institute for Solar Energy Systems ISE, Freiburg im Breisgau, Germany	S 7.5		16:30	Plasma Time Of Flight Mass Spectrometry for power electronics and photonics applications (1) : Y. Mazel, E. Nolot, J.-P. Barnes (2) : A. Tempez, S. Legendre (1) : LETI, CEA, MINATEC Campus and University Grenoble Alpes, Grenoble, FRANCE (2) : HORIBA FRANCE SAS, Palaiseau, FRANCE	S 9.2	
12:00	Lunch			16:45	Characterization of Lipid NanoParticles (LNP) for drug delivery through Transmission Electron Microscopy (TEM) A. Arnould, M. Bacia, F. Caputo, I. Texier, M. Escude, G. Effantin, A.C. Couffin, R. Soulas, J.F. Damlencourt Univ. Grenoble Alpes, F-38000 Grenoble, France CEA, LITEN, MINATEC Campus, F-38054 Grenoble, France , IBS, EPN Science Campus, F-38044 Grenoble, France , Univ. Grenoble Alpes, F-38000 Grenoble, France CEA, LETI, MINATEC Campus, F-38054 Grenoble, France , Univ. Grenoble Alpes, F-38000 Grenoble, France CEA, LETI, MINATEC Campus, F-38054 Grenoble, France , Univ. Grenoble Alpes, F-38000 Grenoble, France CEA, LITEN, MINATEC Campus, F-38054 Grenoble, France , IBS, EPN Science Campus, F-38044 Grenoble, France , Univ. Grenoble Alpes, F-38000 Grenoble, France CEA, LETI, MINATEC Campus, F-38054 Grenoble, France , Univ. Grenoble Alpes, F-38000 Grenoble, France CEA, LITEN, MINATEC Campus, F-38054 Grenoble, France	S 9.3	
	Advanced X-ray methods for nanomaterials : Daniel Abu-Ras and Burkhard Beckhoff			17:00	Nanospherite-driven biomineralization mechanism in aged human bone revealed by complementary analytical methods G. Sarau1,2, P. Milovanovic3,4, E. A. Zimmermann3, A. vom Scheidt3, B. Hoffmann2, T. Yorgan3, M. Schweizer5, M. Amling3, B. Busse3,6, S. Christiansen1,2,7 1. Helmholtz-Zentrum Berlin für Materialien und Energie GmbH, Hahn-Meitner-Platz 1, 14109 Berlin, Germany, 2. Max Planck Institute for the Science of Light, Staudtstr. 2, 91058 Erlangen, Germany, 3. Institute for Osteology and Biomechanics, University Medical Center Hamburg-Eppendorf, Lottestrasse 55a, 22529 Hamburg, Germany, 4. Laboratory for Anthropology, Institute of Anatomy, Faculty of Medicine, University of Belgrade, Dr Subotica 4/2, 11000 Belgrade, Serbia, 5. Center of Molecular Neurobiology, University Medical Center Hamburg-Eppendorf, Martinistrasse 52, 20246 Hamburg, Germany, 6. Materials Sciences Division, Lawrence Berkeley National Laboratory / University of California-Berkeley, CA 94720, USA, 7. Physics Department, Freie Universität Berlin, Arnimallee 14, 14195 Berlin, Germany	S 9.4	
14:00	Modern synchrotron-based XRD microscopy imaging on 300 mm strained Ge / SiGe / Si(001) wafers for sub-10 nm CMOS M. Zöllner1, M.-I. Richard2, T. Schüllli2, G. Chahine2, P. Zaumseil1, G. Capellini1, M. Haeblerlen3, P. Storck3, and T. Schroeder1 1 IHP- Innovation for High Performance Si Microelectronics, Im Technologiepark 25, 15236 Frankfurt (Oder), Germany 2 ID01/ESRF, The European Synchrotron Radiation Facility, 71 Rue Des Martyrs, 38043 Grenoble, France 3 Siltronic AG, Hans Seidel Platz 4, 81737 München, Germany	S 8.1		17:15	Nanoscale chemical mapping of semicrystalline polymers Kerry J Abrams, Nicola Stehling, Cornelia Rodenburg University of Sheffield	S 9.5	
14:30	Model independent approach for the analysis of GIXR data from thin films I. A. Makhotkin1, S.N. Yakunin2, J. F. Woitok3, R.W.E. van de Kruijs1, E. Reuvekamp3 and F. Bijkerk1 Industrial Focus Group XUV Optics, MESA+ Institute for Nanotechnology, University of Twente, Drienerloolaan 5, Enschede, 7522 NB, The Netherlands, NRC Kurchatov Institute, Moscow, Russian Federation, PANalytical B.V., Lelyweg 1, 7602 EA, Almelo, The Netherlands,	S 8.2		17:30	Atomic-level Characterization of Two-dimensional Halide Perovskites Yi Yu,1,2 Dandan Zhang,1,2 Christian Kisielowski,3 Letian Dou,1,2 Nikolay Kornienko,1,2 Yehonadav Bekenstein,1,2 Andrew B. Wong,1,2 A. Paul Alivisatos,1,2,4,5 & Peidong Yang1,2,4,5 1 Department of Chemistry, University of California, Berkeley, CA 94720, USA. 2 Materials Sciences Division, Lawrence Berkeley National Laboratory, Berkeley, CA 94720, USA. 3 The Molecular Foundry, Lawrence Berkeley National Laboratory, Berkeley, CA 94720, USA. 4 Kavli Energy NanoScience Institute, Berkeley, California 94720, USA. 5 Department of Materials Science and Engineering, University of California, Berkeley, CA 94720, USA.	S 9.6	
14:45	Characterization of bio-molecular nano-layers by means of reference-free X-ray Spectrometry Cornelia Streeck (1), Paul M. Dietrich (4), Tobias Fischer(2), Knut Rurack (2), Wolfgang E. S. Unger(2), and Burkhard Beckhoff (1) (1) Physikalisches Technische Bundesanstalt (PTB), Abbestr. 2-1, 10587 Berlin, Germany, (2) Bundesanstalt für Materialforschung und -prüfung (BAM), Unter den Eichen 87, 12205 Berlin, Germany, (3) Technische Universität Berlin, Hardenbergstr. 36, 10623 Berlin, Germany, (4) SPECS Surface Nano Analysis GmbH, Voltastrasse 5, 13355 Berlin, Germany	S 8.3		17:45	Ruthenium growth on B, C and B4C studied by LEIS Andrey Zameshin, Andrey E. Yakshin, Marko Sturm, Fred Bijkerk Industrial Focus Group XUV Optics, MESA+ Institute for Nanotechnology, University of Twente, Enschede, The Netherlands	S 9.7	
15:00	Probing elemental/chemical gradients and adhesion properties of organics on steel by X-ray photoelectron spectroscopy (XPS) T. Greunz1, C. Lowe2, J. Humlicek3-4, B. Strauß5, D. Stifter1 1 ZONA, JKU Linz, Altenberger Straße 69, 4040 Linz, Austria, 2 Becker Industrial Coatings Ltd, Goodlass Road, Speke, Liverpool L24 9HJ, United Kingdom, 3 Central European Institute of Technology, Masaryk University, Kamenice 753/5, 62500 Brno, Czech Republic, 4 Masaryk University, Faculty of Science, Department of Condensed Matter Phys, Kotlarska 2, CS-61137 Brno, Czech Republic, 5 voestalpine Stahl GmbH, voestalpine-Straße 3, 4031 Linz, Austria,	S 8.4			ALTECH Poster Session II : Cornelia Streeck and Nolwenn Fleurence		
15:15	Probing the extreme surface of isolated nanoobjects O. Sublemontier [1], D. Aureau [2], M. Patanen [3], S. Benkoula [4], X.-J. Liu [5], C. Nicolas [4], E. Robert [4], C. Reynaud [1], F.-A. Barreda [1], H. Kintz [1], M.-A. Gaveau [1], J.-L. Le Garrec [6], A. Etcheberry [2], J.B.A. Mitchell [6], and C. Miron [4,7] [1] NIMBE, CEA, CNRS, Université Paris-Saclay, CEA Saclay 91191 Gif-sur-Yvette, France, [2] Institut Lavoisier de Versailles, Université Versailles-St Quentin, UMR CNRS 8180, 78035 Versailles, France, [3] NANOMO research unit, Faculty of Science, P.O. Box 3000, 90014 University of Oulu, Finland, [4] Synchrotron SOLEIL, l'Orme des Merisiers, Saint-Aubin, BP 48, 91192 Gif-sur-Yvette Cedex, France, [5] School of Physics, BeiHang University, No.37 XueYuan Road, HaiDian District, 100191 Beijing, China, [6] IPR, U.M.R. No. 6251 du C.N.R.S., Université de Rennes I, 35042 Rennes, France, [7] ELI-NP, "Horia Hulubei" National Institute for Physics and Nuclear Engineering, Măgurele, Jud. Ilfov, Romania	S 8.5		18:00	Radial distribution function imaging: a new TEM method in resolving the multiphase amorphous materials Xiaoke Mu1,2, Di Wang1,3, Tao Feng4, Christian Kübel1,2,3 1. Institut für Nanotechnologie (INT), Karlsruhe Institute of Technology (KIT), 76344 Eggenstein-Leopoldshafen, Germany, 2. Helmholtz-Institute Ulm for Electrochemical Energy Storage (HIU), Karlsruhe Institute of Technology (KIT), 89081 Ulm, Germany, 3. Karlsruhe Nano Micro Facility (KNMF), Karlsruhe Institute of Technology (KIT), 76344 Eggenstein-Leopoldshafen, Germany, 4. Herbert Gleiter Institute of Nanoscience, Nanjing University of Science and Technology (NJUST), Nanjing, China,	S 10-P.1	
15:30	Coffee Break			18:00	Laboratory instrumentation for high resolution X-ray spectroscopy analysis of materials Wolfgang Malzer, Daniel Grötzsch, Christopher Schlesiger, Richard Gnewkow, Birgit Kanngießer Technische Universität Berlin, IOAP, Hardenbergstr. 36, 10623 Berlin, Germany	S 10-P.2	
	Electron Beam and Ion Beam Characterisation : Cor Claeys						
16:00	Elemental analysis of the outer layer of nano materials using Low Energy Ion Scattering Thomas Grehl ION-TOF GmbH, Heisenbergstr. 15, 48149 Münster, Germany	S 9.1					